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		AE	5,282,946	02-1994	Kinoshita et al.						
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		AG	5,809,393	09-1998	Duniop et al.						
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		A1 5,468,401		11-1995	Lum						
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	NW	AN	9201080 '	01/1992	PCT		C23C 14/	35			
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	WH	AR	C. Klein et al., "Ma	moai or Minerale	8. hh 32-40 .			<u> </u>	· · - · · · ·		
	HW	AS	Tungsten and Refra	etory Metals 2.	Temperature on the Texture of I	Rolled Tantalum and I	antulum-10 Wt.98	6 Tungstu	n, reprinted (. rom	
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	AE	5,074,907	12-1991	Amato et al.						
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1	AK	5,418,071	05-1995	Satou et al.						
M	AL	5,508,000	04-1996	Satou et al.				<u> </u>		
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1		AB	4,842,706	06-1989	Fukasawa et al.					
		AC	4,960,163	10-1990	Fang et al.					
·		AD	5,850,755	12-1998	Segal					
		AE	5,456,815	10-1995	Fukuyo et al.					
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MC		AL	5,798,005	08-1998	Murata et al.					
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N)	AS	Hatch, J.E., <u>ALUMI</u>	NUM. 1984, Cha	p. 5, "Metallurgy of Heat Treatme	nt and General Princip	oles of Precipi	ation Hard	ening", pp. 13	4-
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1	АВ	3,65	3,981	04-1972	Watanabe et al.					
	AC	3,84	9,212	11-1974	Thornburg					
	AD	5,76	6,380	06-1998	Lo et al.					
	AE	6,12	3,896	09-2000	Mecks, III et al.					
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	Ai 5,772,795		06-1998	Lally et al.						
	Ŋ	6,22	1,178 B1	04-2001	Torizuka et al.					
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144	AQ		01/29279 A1	26.04.2001	PCT					
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	AB	5,623,726	04-1997	Kiiski et al.					
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HW	AS	Arh, Jr., "Sulfonatic 541-564, (1993, Yea	on and Sulfonation is sufficiently c	on to Thorium and Thorium Compearly so that the month is not an is	ounds" Kirk-Othmer E	incyclopedia	of chemic	cal Technology	vol. 22, pp.
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	AJ		National Research	Corporation Dat	a Sheet "SGS Tatalum", pgs. 1-7,	no date.					
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	AK		"Nickel, Cobalt and	Their Alloys",	pub. By ASM International, Decem	nber 2000, pages 76, 2	30-234.				
1 WW		<u> </u>									
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	AJ .	¥W	Wright et al., "Text	ure Gradient Eff	ects in Tantalum", International (Conference on Textures	of Material	s, 7 pgs., Sept	ember 1993	
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